

1FCW



PATENT APPLICATION
Docket No.:BGJ-102
Confirmation No. 1586

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Georg Muller

Application No.: 10/663,448

Group Art Unit: 2829

Filed: 9/16/2003

Examiner: Emily Y Chan

For: Semiconductor Device Testing Apparatus, Semiconductor Device Testing System, And
Semiconductor Device Testing Method For Measuring And Trimming The Output Impedance Of
Driver Devices

CERTIFICATE OF MAILING	
I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to Mail Stop Amendment, Commissioner for Patents, Alexandria, VA 22313-1450	
on <u>January 13, 2005</u> Date	<u>Jacqueline M. Arendt</u> Signature
<u>Jacqueline M. Arendt</u> Typed or printed name of person signing certificate	

REPLY TO RESTRICTION REQUIREMENT

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This Reply is submitted in response to the Office Action mailed from the
Patent and Trademark Office on December 13, 2004.